

Thursday, September 16, 2010
5:10 PM

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Office hours:
10:30-12 on Tuesdays in Cory 481

Today:
Oxidation and diffusion
HW#2

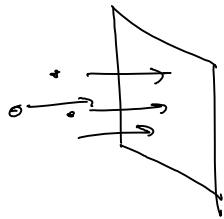
Modeling oxidation

(e.g. the thermal growth of Si_3N_4 over Si)

⇒ The growth rate decreases as time goes on.

Q: What is diffusion?

A:



How many particles pass through a unit area per unit time.
e.g. 5×10^{12} molecules/cm²/s

The diffusion rate (i.e. the time rate of particle flux) $\sim [\text{particles}/(\text{area} \cdot \text{time})]$ and direction are described by Fick's first law of diffusion:

$$\vec{J}(x, y, z, t) = -D \nabla N(x, y, z, t)$$

* Recall: $\nabla N = \frac{\partial N}{\partial x} \hat{x} + \frac{\partial N}{\partial y} \hat{y} + \frac{\partial N}{\partial z} \hat{z}$; $\hat{x}, \hat{y}, \hat{z}$ are unit vectors

Where D is the diffusion coefficient [cm²/s] and N is the particle concentration [cm⁻³].

If $\frac{\partial N}{\partial y} = \frac{\partial N}{\partial z} = 0$, this equation simplifies to:

$$\vec{J}(x, t) \sim -D \frac{\partial N(x, t)}{\partial x}$$

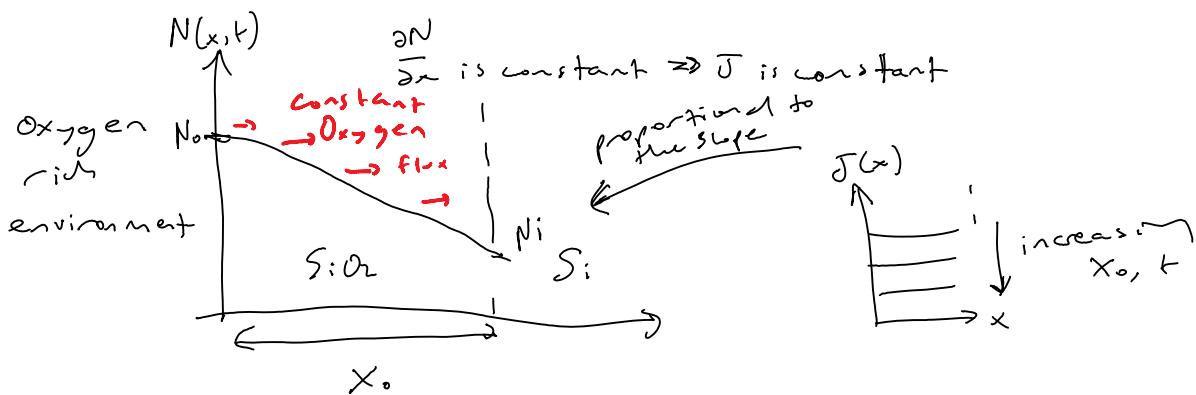
$$J(x,t) = -D \frac{\partial N(x,t)}{\partial x}$$

Intuition: Particles move from regions of high concentration to regions of low concentration due to random thermal motion.

Objective:

Derive the oxide thickness as a function of t.

For silicon oxidation, assume the oxygen flux is constant everywhere in the oxide. (Oxygen does not accumulate.)



Where x_0 is the thickness and N_s and N_i are the oxygen concentrations at the oxide's surface and Si-Si₃O₄ interface respectively.

At the interface,

$$J = k_s N_i \Rightarrow N_i = \frac{J}{k_s}, \quad k_s \text{ is the reaction rate.}$$

Substitute,

$$\Rightarrow J = -D \left(\frac{\partial N}{\partial x} \right) = -D \left(\frac{N_s - N_i}{x_0} \right)$$

$$\begin{aligned} J \left(1 + \frac{D}{k_s x_0} \right) &= \frac{D N_s}{x_0} \\ \Rightarrow J &= \frac{-D N_s}{x_0 + \frac{D}{k_s}} \end{aligned}$$

The rate of change of oxide thickness equals the oxidizing flux divided by the number of

molecules M incorporated into a unit volume in the oxide.

$$\frac{dX_o}{dt} = \frac{J}{M} = \frac{DN_o}{M(X_o + \frac{D}{ks})} \sim \left[\frac{\pi}{cm^2 \cdot s} \cdot \frac{cm^3}{\#} \right] = \left[cm/s \right] \checkmark$$

$$\Rightarrow \frac{M}{DN_o} \left(X_o + \frac{D}{ks} \right) dX_o = dt$$

$$\int_{X_i}^{X_o} \frac{M X_o}{DN_o} + \frac{D}{ks} dX_o = \int_{t_i}^{t_o} dt = t$$

$$\Rightarrow \left(\frac{M X_o^2}{2DN_o} + \frac{M X_o}{N_o ks} \right) - \left(\frac{M X_i^2}{2DN_o} + \frac{M X_i}{N_o ks} \right) = t$$

$$\Rightarrow \tau = \frac{M X_i^2}{2} + \frac{D X_i}{N_o ks}, \text{ Time required to achieve initial oxide thickness } X_i$$

$$t = \frac{M X_o^2}{2DN_o} + \frac{M X_o}{N_o ks} - \tau \quad \text{additional time required to achieve a thickness } X_o.$$

Note: You can choose $X_i=0$, $\tau=0$ if you'd like.

$$t + \tau = \frac{M X_o^2}{2DN_o} + \frac{M X_o}{N_o ks}, \text{ time required to grow to a thickness of } X_o.$$

$$\frac{M X_o^2}{2DN_o} + \frac{M X_o}{N_o ks} - (t + \tau) = 0 \quad \text{Use the quadratic formula}$$

$$X_o(t+\tau) = -\frac{M}{N_o ks} \pm \sqrt{\frac{M^2}{N_o^2 ks^2} + 2 \frac{M}{DN_o} (t + \tau)} \quad \begin{matrix} (DN_o) \\ \frac{M}{DN_o} \\ (\frac{DN_o}{M}) \end{matrix}$$

$$= -\frac{D}{ks} + \sqrt{\frac{D^2}{ks^2} + 2 \frac{DN_o}{M} (t + \tau)}$$

(Jaeger)

$$A = \frac{2D}{ks}$$

$$B = \frac{2DN_o}{M}$$

$$\Rightarrow X_o(t+\tau) = \frac{D}{ks} \left[\sqrt{1 + 2 \frac{N_o ks^2}{DN_o} (t + \tau)} - 1 \right]$$

* Recall: $\sqrt{1+x} = 1 + \frac{x}{2} \text{ if } x \ll 1.$

Two useful simplifications:

Reaction rate limited regime:
 If $t + \tau \ll \frac{DM}{2k_B N_0}$, then $X_0(t + \tau) \approx \frac{k_B N_0}{M} (t + \tau)$

Diffusion rate limited regime:

If $t + \tau \gg \frac{DM}{2k_B N_0}$, then $X_0(t + \tau) \approx \sqrt{\frac{2D N_0}{m} (t + \tau)}$

$$D(E_A, T, \theta_0) = D_0 e^{-E_A/kT}$$

D depends on (100) or (111)
orientation

⇒ Huge temperature dependence.

See Tay p. 47.

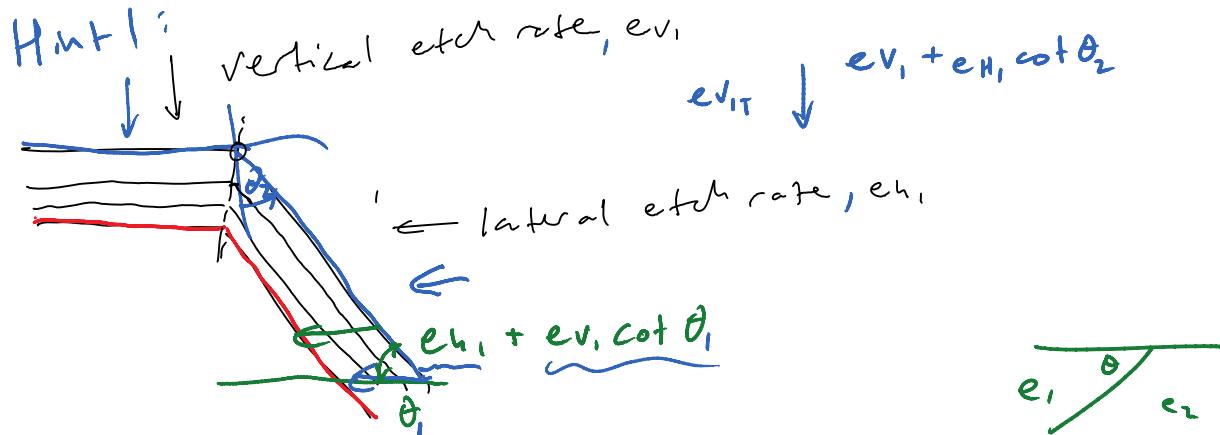
Homework #2

Topics:

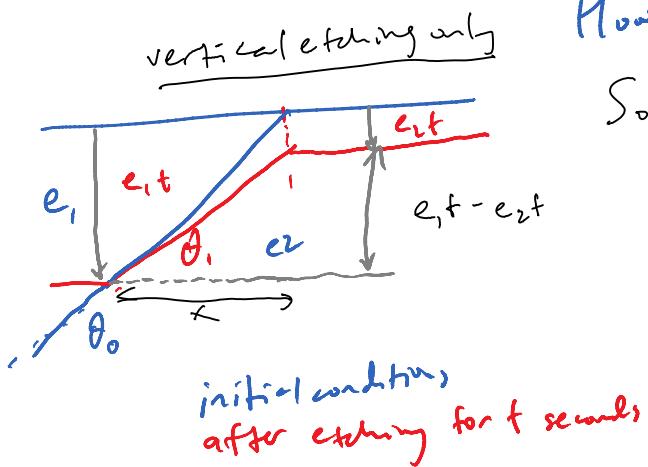
- ① etching
- ② diffusion & sheet resistance.
- ③ lithography

Hints:

- ① etching problem.



Hint 2:



How can we define θ_1 in terms of θ_0 ?

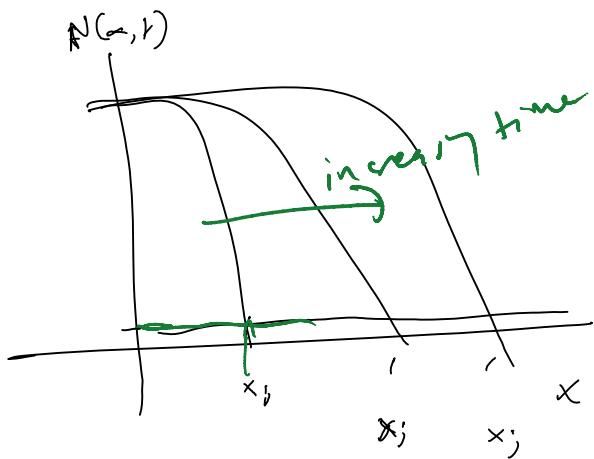
$$\text{Solution: } \tan \theta_0 = e_1 t / x$$

$$\tan \theta_1 = (e_1 t - e_2 t) / x$$

$$\Rightarrow \frac{\tan \theta_1}{e_1 t - e_2 t} = \frac{\tan \theta_0}{e_1 t}$$

$$\Rightarrow \boxed{\theta_1 = \tan^{-1} \left(\tan \theta_0 \left(\frac{e_1 - e_2}{e_1} \right) \right)}$$

② Diffusion



Hint 1: Assume a constant source diffusion.

Hint 2: Can you express D_t as an integral?

Hint 3: a) Use a numerical solver.

Hint 4: b) Integrate over the depth of the diffusion.

$$c) R_d = \left(\int_0^{x_i} q_m N_0(x) dx \right)^{-1} \approx \Sigma$$

$$1.6 \times 10^{-19} C$$

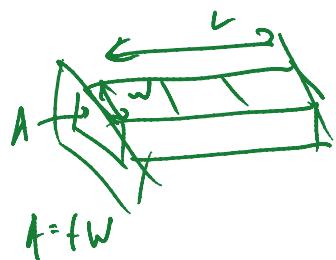
$$R = R_d \cdot \# \text{ of squares}$$

$$R = R_d \cdot \# \text{ of squares} (\text{in series})$$

$$R = \frac{P_L}{A} = \frac{P_L}{t \omega} = f_f \int_{\omega}^{\infty} w(r) dr$$

$$1 \text{ square corner} \\ = 0.5 b \boxed{17}$$

$$R = \frac{F}{A} = f \cdot w \cdot t = 0.5 \text{ b L}$$



$$R = \frac{\rho L}{A} = \frac{\rho \cdot L}{t \cdot w} = \frac{\rho \cdot L}{w^3}$$

- ③ Assume "underexposed" and "overexposed"